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PATENT NUMBER and
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U.S. UTILITY Patent Application

APPL NUM	FILING DATE	CLASS	SUBCLASS	GAU	EXAMINER
10050776	01/18/2002	359		2633	

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**CONTINUING DATA VERIFIED:

No

**FOREIGN APPLICATIONS VERIFIED:

JAFAN 2001-056547 03/01/2001

PG-PUB	DO NOT PUBLISH <input type="checkbox"/>	RESCIND <input type="checkbox"/>	
Foreign priority claimed 35 USC 119 conditions met Verified and Acknowledged Examiner's initials <i>JK</i>		<input checked="" type="checkbox"/> yes <input type="checkbox"/> no <input checked="" type="checkbox"/> yes <input type="checkbox"/> no	ATTORNEY DOCKET NO 520.41064X00
TITLE : Apparatus and method for inspecting defects			
U.S. DEPT. OF COMM./PAT. & TM-PTO-425L(Rev. 12-94)			

NOTICE OF ALLOWANCE MAILED		Assistant Examiner	CLAIMS ALLOWED	
			Total Claims	Print Claim for O.G.
ISSUE FEE		DRAWING		
Amount Due	Date Paid	Sheets Drwg.	Figs.Drwg.	Print Fig.
		Application Examiner		
<input type="checkbox"/> TERMINAL DISCLAIMER		PREPARED FOR ISSUE		
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